Call for Papers

2008 IEEE Circuits and Systems International Conference on Testing and Diagnosis (ICTD'08)

25-26 October 2008, Chengdu, China

- ***Sponsor:***

IEEE Circuits and Systems Society (CAS)

- ***Technical Co-sponsor:***

University of Electronic Science and Technology of China (UESTC)

Chinese Institute of Electronics (CIE)
China Instrument & Control Society (CIS)

- ***Organizers:***

University of Electronic Science and Technology of China (UESTC)

We are delighted to announce that the 2008 IEEE Circuits and Systems International Conference on Testing and Diagnosis (ICTD'08), sponsored by IEEE Circuit and System Society (CAS), will be held on 25th -26th Oct. 2008 in Chengdu P. R. China.

Prof. Rueywen Liu, a General Chair of ICTD'08, is a Chair Professor of the University of Notre Dame, a Life Fellow of IEEE, and a former President of IEEE CAS. ICTD'08 will invite a list of distinguished keynote speakers. Among them, Professor Chenming Hu is a Member of US National Academy of Engineering, a foreign member of Chinese Academy of Science, a fellow of IEEE and a Chair Professor of University of California, Berkeley.

ICTD'08 invites submissions on the latest techniques for testing and diagnosis on topics that are related but not limited to the following. Submissions should be original, unpublished papers describing recent work. **The papers in the proceedings of ICTD'08 are published by IEEE Xplore and indexed by EI and DOI.**

- ✧ ATE/TPS Techniques
- ✧ Next Generation Instruments and Systems
- ✧ Board and System Test and Diagnosis
- ✧ System-on-Chip test
- ✧ RF/MW/MM Test and Instrument
- ✧ Data Acquisition
- ✧ Monitoring, Diagnosis and Prognostics methods
- ✧ Design-for-Test (DFT)
- ✧ BIT/BIST
- ✧ Test Generation
- ✧ Fault Tolerance
- ✧ Mixed-Signal and Analog Test
- ✧ High-Speed Digital Test
- ✧ Fault Model and Fault Simulation
- ✧ Optoelectronics Test
- ✧ Reliability and Design for Reliability
- ✧ Diagnosis for Analog Circuits
- ✧ Test and Diagnosis for Submicron Circuits
- ✧ Test and Diagnosis of Biomedical CAS
- ✧ Other Related Topics

Time Table:

Paper Submission Deadline	**June 15, 2008**
Notification of Acceptance	**August 5, 2008**
Final Paper Submission Deadline	**August 20, 2008**

Language:

English will be the official Language at the Conference.

Submission Guidelines:

The ICTD'2008 will focus on the challenges of providing high-quality, cost-effective, life-cycle tests, automated fault diagnosis and developing or adapting new test approaches to meet the ongoing demands of new technology. Prospective Authors are invited to submit original, unpublished papers describing recent work in the field of testing and diagnosis. Submissions must include:

- Title of papers.
- Name, affiliation, mailing address, email address, telephone and fax number of each author.
- Designation of the presenters, so that ICTD08 will communicate with the presenters.
- An electronic copy of complete papers of four (4) pages maximum

Prospective authors should read the detailed instructions regarding formats and submission requirements that are available on the ICTD Web site at: http://ictd08.uestc.edu.cn

Proceedings:

ICTD maintains a highly competitive selection process for papers presented. Submissions should clearly describe the status of the reported work, its significance and highlights, supporting data, results and conclusions, and reference to prior work must also be included. All of the accepted papers will be edited as proceedings of ICTD'2008. **The papers in the proceedings of ICTD'08 are published by IEEE Xplore and indexed by EI and DOI.**.

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